

DATASHEET

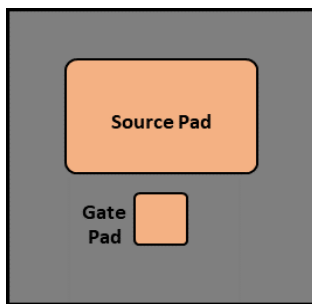
# UJ3N1701K2

## 1700V-1.1Ω SiC Normally-on JFET

Rev. A, February 2020

### Description

UnitedSiC offers the high-performance G3 SiC normally-on JFET transistors. This series exhibits ultra-low on resistance ( $R_{DS(ON)}$ ) and gate charge ( $Q_G$ ) allowing for low conduction and switching loss. The device normally-on characteristics with low  $R_{DS(ON)}$  at  $V_{GS} = 0\text{ V}$  is also ideal for current protection circuits without the need for active control, as well as for cascode operation.



### Features

- ◆ Typical on-resistance  $R_{DS(on),typ}$  of 1.1Ω
- ◆ Voltage controlled
- ◆ Maximum operating temperature of 175°C
- ◆ Extremely fast switching not dependent on temperature
- ◆ Low gate charge
- ◆ Low intrinsic capacitance
- ◆ RoHS compliant

### Typical applications

- ◆ Over Current Protection Circuits
- ◆ DC-AC Inverters
- ◆ Switch mode power supplies
- ◆ Power factor correction modules
- ◆ Motor drives
- ◆ Induction heating

Part Number	Package
UJ3N1701K2Z	Die on tape
UJ3N1701K2	Undiced wafer



## Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	$V_{DS}$		1700	V
Gate-source voltage	$V_{GS}$	DC	-20 to +3	V
		AC <sup>1</sup>	-20 to +20	V
Continuous drain current <sup>2,3</sup>	$I_D$	$T_C = 25^\circ\text{C}$	3.4	A
		$T_C = 100^\circ\text{C}$	2.7	A
Pulsed drain current <sup>3,4</sup>	$I_{DM}$	$T_C = 25^\circ\text{C}$	6	A
Maximum junction temperature <sup>5</sup>	$T_{J,max}$		175	$^\circ\text{C}$
Operating and storage temperature	$T_J, T_{STG}$		-55 to 175	$^\circ\text{C}$

1. +20V AC rating applies for turn-on pulses <200ns applied with external  $R_G > 1\Omega$ .

2. Limited by  $T_{J,max}$

3. Assumes a maximum junction-to-case thermal resistance of  $2.6^\circ\text{C/W}$

4. Pulse width  $t_p$  limited by  $T_{J,max}$

5. Package limited

## Electrical Characteristics ( $T_J = +25^\circ\text{C}$ unless otherwise specified)

### Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Drain-source breakdown voltage	$BV_{DS}$	$V_{GS} = -20\text{V}, I_D = 1\text{mA}$	1700			V
Total drain leakage current	$I_{DSS}$	$V_{DS} = 1700\text{V}, V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		3.5	12	$\mu\text{A}$
		$V_{DS} = 1700\text{V}, V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		35		
Total gate leakage current	$I_{GSS}$	$V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		0.2	1.2	$\mu\text{A}$
		$V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		0.8		$\mu\text{A}$
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS} = 2\text{V}, I_D = 0.5\text{A}, T_J = 25^\circ\text{C}$		1.0		$\Omega$
		$V_{GS} = 0\text{V}, I_D = 0.5\text{A}, T_J = 25^\circ\text{C}$		1.1	1.4	
		$V_{GS} = 2\text{V}, I_D = 0.5\text{A}, T_J = 175^\circ\text{C}$		2.2		
		$V_{GS} = 0\text{V}, I_D = 0.5\text{A}, T_J = 175^\circ\text{C}$		2.4		
Gate threshold voltage	$V_{G(th)}$	$V_{DS} = 5\text{V}, I_D = 1.5\text{mA}$	-14	-11.5	-8	V
Gate resistance	$R_G$	$f = 1\text{MHz}, \text{open drain}$		14.5		$\Omega$

## Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Input capacitance	$C_{iss}$	$V_{DS}=100V, V_{GS}=-20V$ $f=100kHz$		76.5		pF
Output capacitance	$C_{oss}$			10.1		
Reverse transfer capacitance	$C_{rss}$			7		
Effective output capacitance, energy related	$C_{oss(er)}$	$V_{DS}=0V$ to 1200V, $V_{GS}=-20V$		6.3		pF
$C_{oss}$ stored energy	$E_{oss}$	$V_{DS}=1200V, V_{GS}=-20V$		4.6		$\mu J$
Total gate charge	$Q_G$	$V_{DS}=1200V, I_D=2.5A,$ $V_{GS} = -18V$ to 0V		11		nC
Gate-drain charge	$Q_{GD}$			6		
Gate-source charge	$Q_{GS}$			1.3		
Turn-on delay time	$t_{d(on)}$	$V_{DS}=1200V, I_D=2.5A,$ Gate Driver = -18V to 0V, $R_G=1\Omega,$ Inductive Load, FWD: 2x UJ3D1202TS in series $T_J=25^\circ C$		6		ns
Rise time	$t_r$			12		
Turn-off delay time	$t_{d(off)}$			6		
Fall time	$t_f$			46		
Turn-on energy	$E_{ON}$	FWD: 2x UJ3D1202TS in series $T_J=25^\circ C$		59		$\mu J$
Turn-off energy	$E_{OFF}$			24		
Total switching energy	$E_{TOTAL}$			83		
Turn-on delay time	$t_{d(on)}$	$V_{DS}=1200V, I_D=2.5A,$ Gate Driver = -18V to 0V, $R_G=1\Omega,$ Inductive Load, FWD: 2x UJ3D1202TS in series $T_J=150^\circ C$		6		ns
Rise time	$t_r$			11		
Turn-off delay time	$t_{d(off)}$			6		
Fall time	$t_f$			38		
Turn-on energy	$E_{ON}$	FWD: 2x UJ3D1202TS in series $T_J=150^\circ C$		58		$\mu J$
Turn-off energy	$E_{OFF}$			18		
Total switching energy	$E_{TOTAL}$			76		

### Typical Performance Diagrams

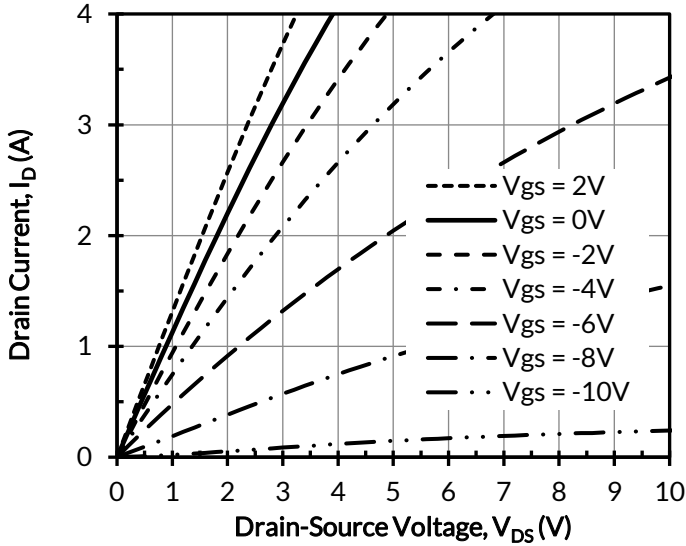


Figure 1. Typical output characteristics at  $T_j = -55^\circ\text{C}$ ,  $t_p < 250\mu\text{s}$

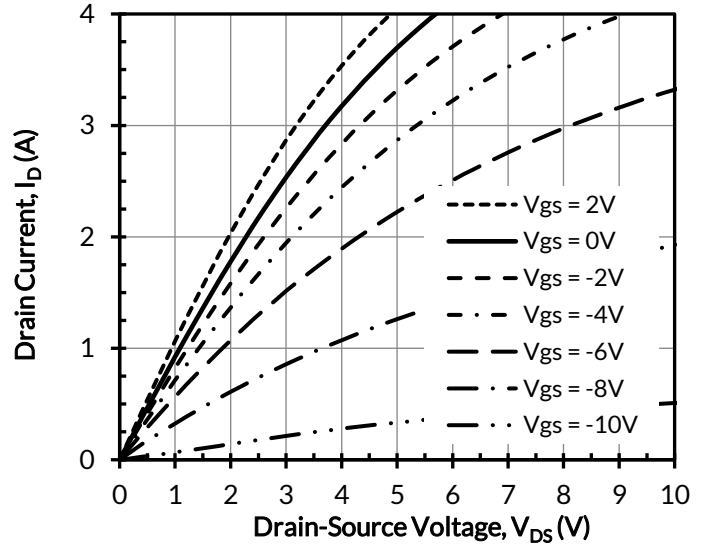


Figure 2. Typical output characteristics at  $T_j = 25^\circ\text{C}$ ,  $t_p < 250\mu\text{s}$

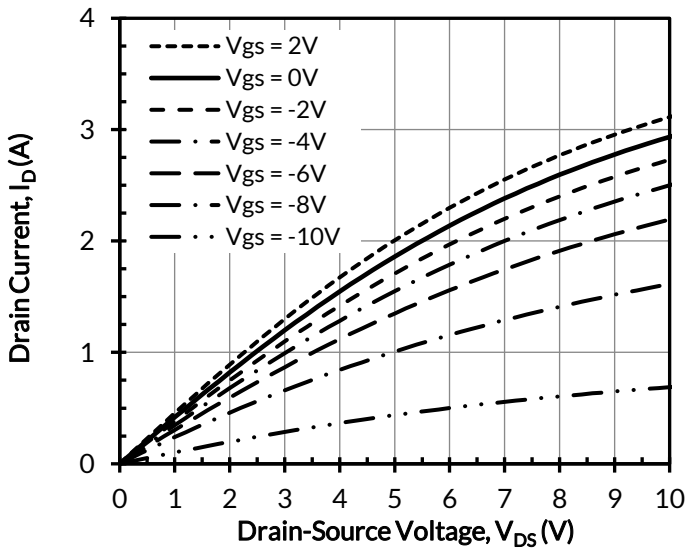


Figure 3. Typical output characteristics at  $T_j = 175^\circ\text{C}$ ,  $t_p < 250\mu\text{s}$

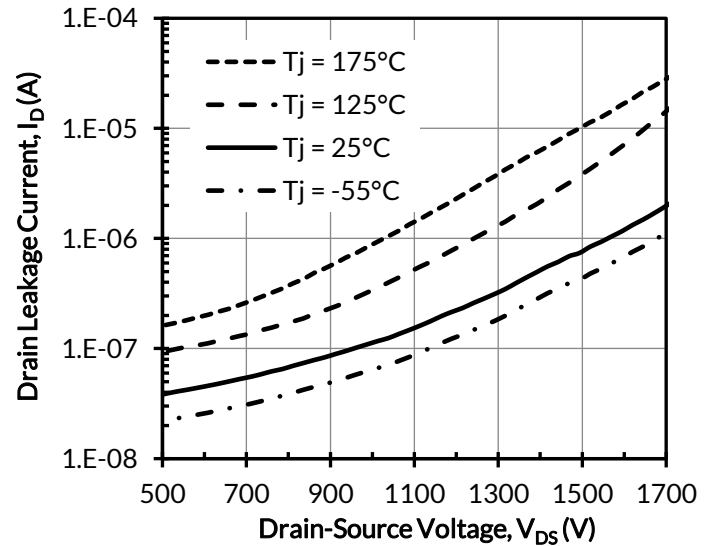


Figure 4. Typical drain-source leakage at  $V_{GS} = -20\text{V}$

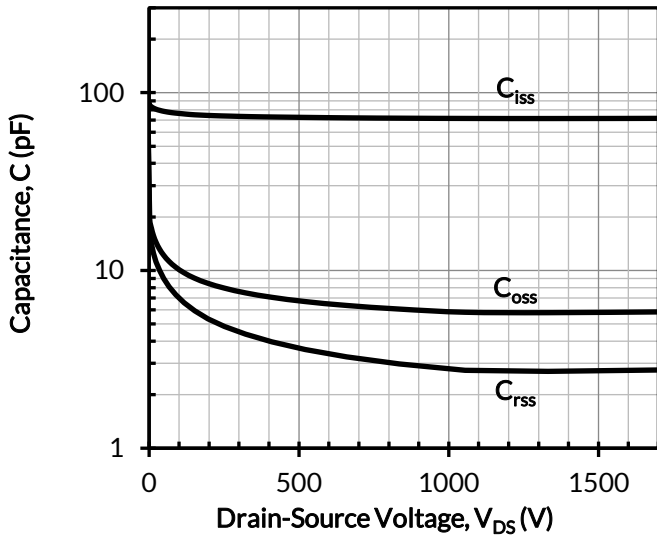


Figure 5. Typical capacitances at  $f = 100\text{kHz}$  and  $V_{GS} = -20\text{V}$

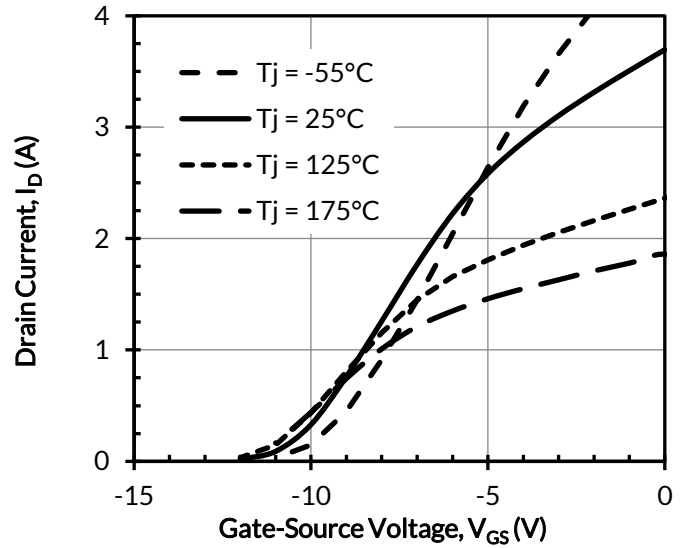


Figure 6. Typical transfer characteristics at  $V_{DS} = 5\text{V}$

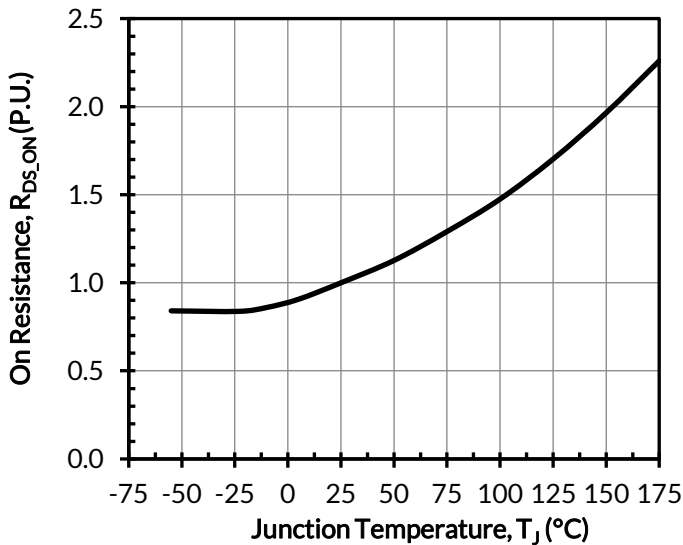


Figure 7. Normalized on-resistance vs. temperature at  $V_{GS} = 0\text{V}$  and  $I_D = 0.5\text{A}$

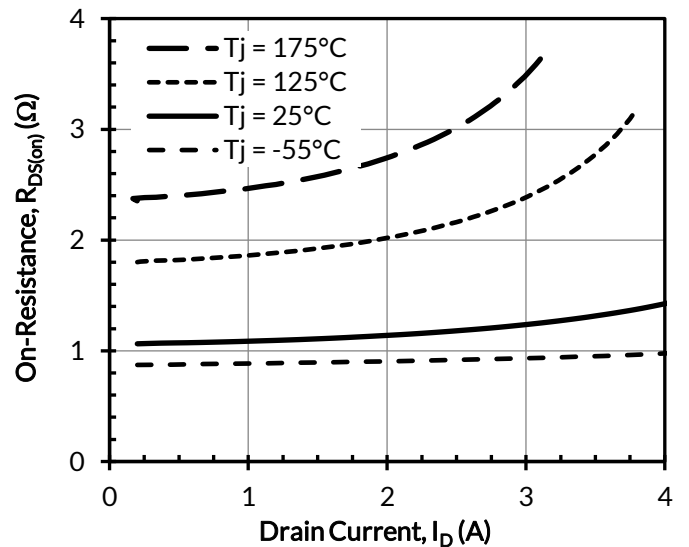


Figure 8. Typical drain-source on-resistances at  $V_{GS} = 0\text{V}$

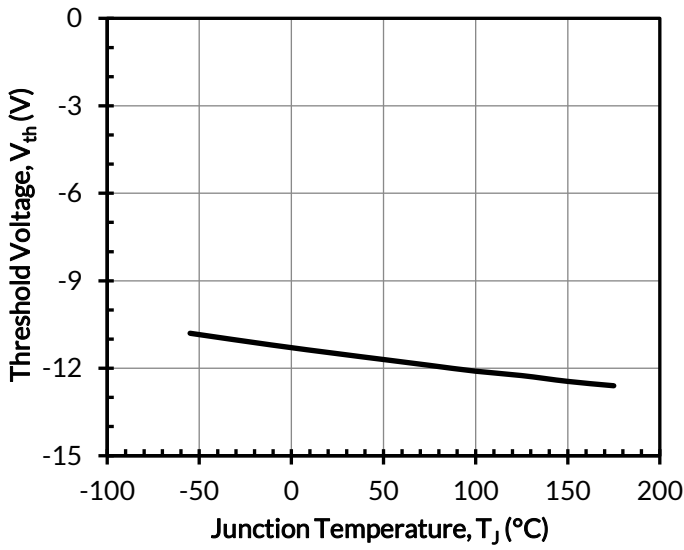


Figure 9. Threshold voltage vs. junction temperature at  $V_{DS} = 5V$  and  $I_D = 1.5mA$

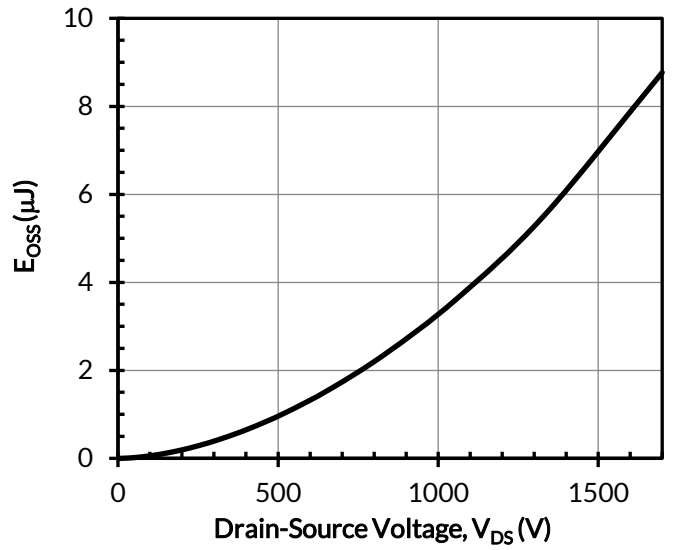


Figure 10. Typical stored energy in  $C_{OSS}$  at  $V_{GS} = -20V$

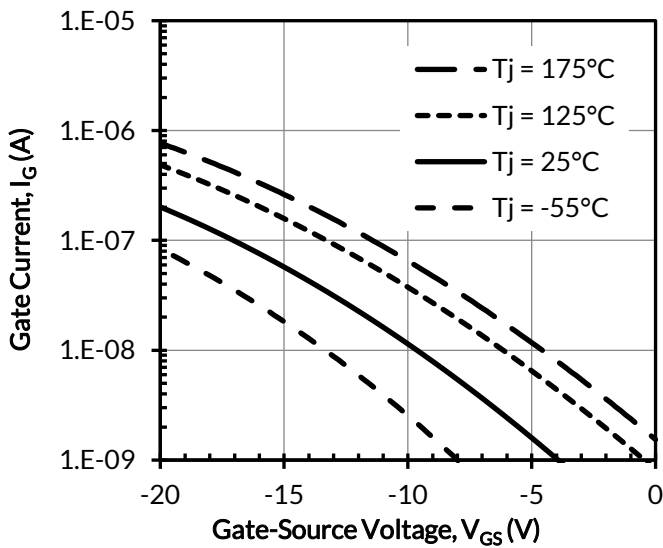


Figure 11. Typical gate leakage at  $V_{DS} = 0V$

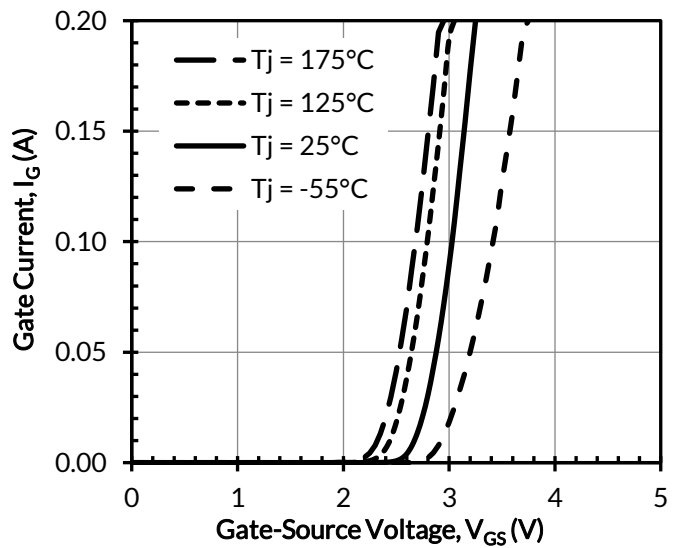


Figure 12. Typical gate forward current at  $V_{DS} = 0V$

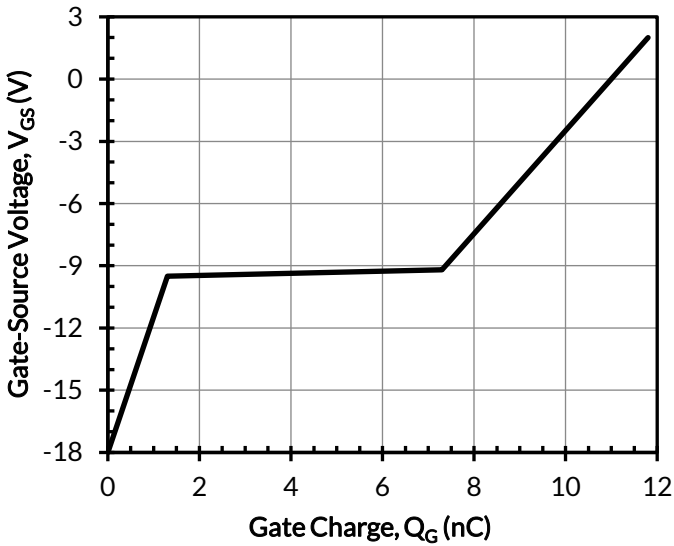


Figure 13. Typical gate charge at  $V_{DS} = 1200V$  and  $I_D = 2.5A$

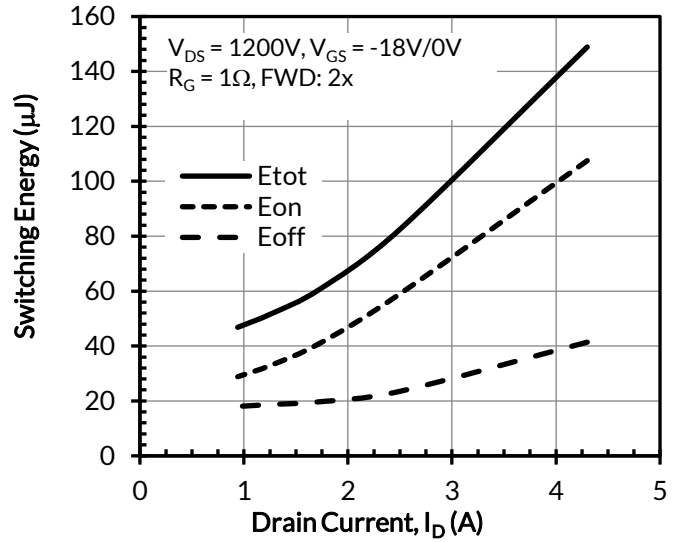


Figure 14. Clamped inductive switching energy vs. drain current at  $T_J = 25^\circ C$

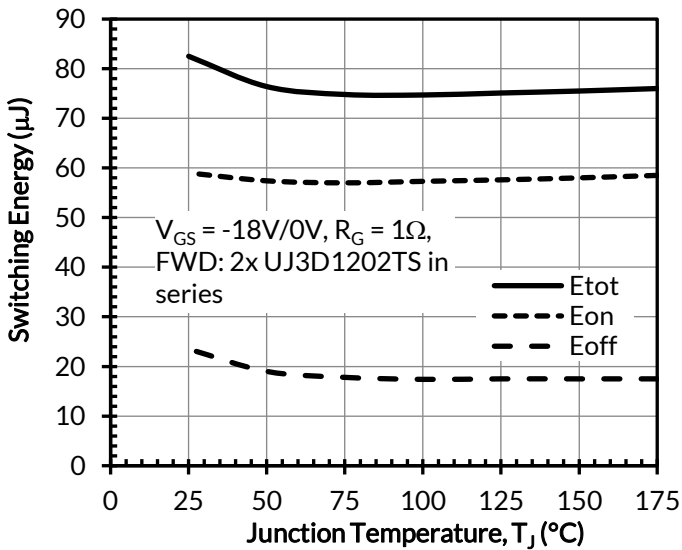


Figure 15. Clamped inductive switching energy vs. junction temperature at  $V_{DS} = 1200V$  and  $I_D = 2.5A$

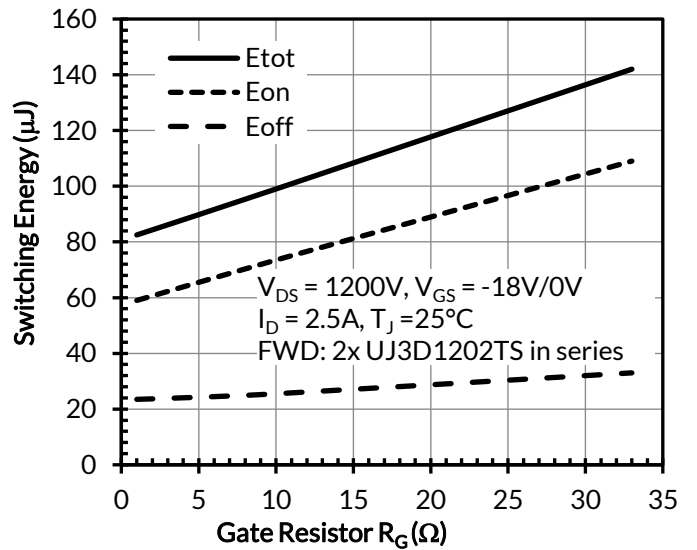
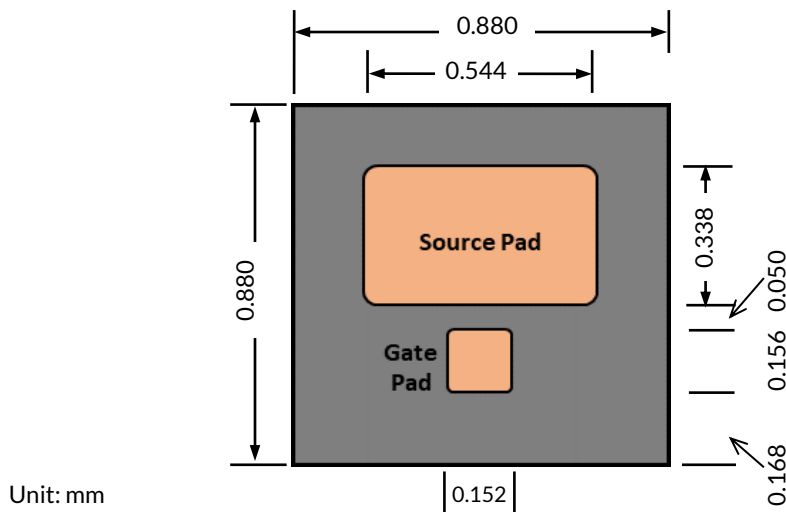


Figure 16. Clamped inductive switching energy vs. gate resistor  $R_G$

## Mechanical Characteristics

Parameter	Typical Value	Units
Die dimensions with scribe line (L x W)	0.880 x 0.880	mm
Scribe line width	80	μm
Source pad metal dimensions (L x W)	0.544 x 0.338	mm
Gate pad metal dimensions (L x W)	0.152 x 0.156	mm
Source metallization (AlCu)	5	μm
Gate metallization (AlCu)	5	μm
Backside drain metallization (Ti/Ni/Ag)	0.1/0.2/1	μm
Frontside passivation	Polyimide	
Die thickness	150	μm
Wafer size	150	mm
Gross die per wafer	18,656	

## Chip Dimensions



## Disclaimer

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